

For Immediate Release



Xcerra Test Cell Qualified for Barometric Test at Major European IDM

Optimized for high yield, low cost and greatest flexibility

Norwood, January 2018: Xcerra continues to expand its TCI (Test Cell Innovation) customer base after completing a qualification at a major European IDM for a fully integrated and prevalidated test cell for barometric sensor test. The solution consists of a Multitest InStrip handler with InBaro module, an LTX-Credence Diamondx ATE and Multitest contactors. In addition a third party pressure stimulus as well as dedicated third party interface boards have been integrated by Xcerra.

The project has been driven by the customer's desire to standardize on a test platform for MEMS sensors that provides high throughput, parallelism and accuracy. The implementation has been proven to support very small deltas in temperature and reference voltage seen by the DUT and reference sensor, which is necessary for successful calibration.

With Xcerra's integrated and prevalidated test cell the customer benefits from high parallelism and throughput for lower cost of test. The highly stable pressure, temperature and reference voltage allows for precise calibration and higher yields. Fast settling times for multiple pressure changes allow for higher throughput. The Xcerra TCI project of integrating of the InStrip handler and the Diamondx ATE (serial and GPIB communications) has been combined with the performance optimization of the InBaro test module for this specific application. The deployed low force Pogo pin contacting solution and the highly reliable InCarrier handling ensure highest yield of the sensitive and small packages used for this application.

For future business the customer is able to fully leverage the great flexibility of Xcerra's TCI solution to redeploy the equipment for other sensor applications and use the Multitest InCarrier for WLCSP devices.

To learn more about the Xcerra Test Cell Innovation, please visit www.Xcerra.com/TCI

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About Xcerra

Xcerra Corporation is comprised of four powerful brands in the semiconductor and electronics manufacturing test markets: atg-Luther & Maelzer, Everett Charles Technologies, LTX-Credence and Multitest. The combination of these businesses creates a Company with a broad spectrum of semiconductor and PCB test expertise that drive innovative new products and services, and the ability to deliver to customers fully integrated semiconductor test cell solutions. The Company addresses the broad, divergent requirements of the mobility, industrial, automotive and consumer end markets, offering a comprehensive portfolio of solutions and technologies, and a global network of strategically deployed applications and support resources. Additional information can be found at www.xcerra.com or at each product group's website; www.atg-lm.com, www.ectinfo.com, www.ltxc.com and www.multitest.com.

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